

		Docket No. <b>52433/795</b>	Application No. <b>10/534,858</b>
		Applicant(s) <b>HASHIMURA et al.</b>	Examiner <b>Deborah Yee</b>
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**U. S. PATENT DOCUMENTS**

EXAMINER INITIAL	PATENT/PUBLICATION NUMBER	PATENT/PUBLICATION DATE mm/dd/yyyy	NAME	CLASS	SUBCLASS	FILING DATE*

**FOREIGN PATENT DOCUMENTS**

EXAMINER INITIAL	DOCUMENT NUMBER	DATE mm/dd/yyyy	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
						Yes	No
	2002-249823	09/06/2002	JP			Abstract	
	11-293391	10/26/1999	JP			Abstract	
	2002-3991	01/09/2002	JP			Abstract	
	2000-160284	06/13/2000	JP			Abstract	
	2000-319753	11/21/2000	JP			Abstract	

**OTHER DOCUMENTS**

EXAMINER INITIAL	AUTHOR, TITLE, DATE, PERTINENT PAGES, ETC.
	Japanese Office Action dated September 12, 2008 issued in corresponding Japanese Application No. 2003-374489.
	Japanese Office Action dated September 12, 2008 issued in corresponding Japanese Application No. 2003-374517.

EXAMINER	DATE CONSIDERED
EXAMINER: Initial if citation considered, whether or not citation is in conformance with M.P.E.P. 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	